

#### Features

- High Power GaN HEMT for DC to 3.8GHz
- High Power: 17W @ 3.8GHz
- High Efficiency: 56% @ 3.8GHz
- DFN Plastic Package

## Description



Sumitomo Electric's GaN-HEMT SGNL015Z2K-R offers high power, high efficiency, ease of matching and greater consistency for DC to 3.8GHz Radar applications with 50V operation. SGNL015Z2K-R is suitable for broadband applications.

#### ABSOLUTE MAXIMUM RATINGS (Case Temperature T<sub>c</sub>=25deg.C)

Item	Symbol	Rating	Unit
Operating-Voltage V <sub>DS</sub>		55	V
Drain-Source Voltage V <sub>DS</sub>		160 @ V <sub>GS</sub> -8V	V
Gate-Source Voltage V <sub>GS</sub>		-15	V
Total Power Dissipation	Pt	27	W
Storage Temperature	T <sub>stg</sub>	-40 to +125	deg.C
Channel Temperature	T <sub>ch</sub>	+250	deg.C

#### **RECOMMENDED OPERATING CONDITION**

Item	Symbol	Condition	Limit	Unit
DC Input Voltage	V <sub>DS</sub>		<=50	V
Forward Gate Current	$I_{GF}$	RG=15ohm	<=7.49	mA
Reverse Gate Current	I <sub>GR</sub>	RG=15ohm	>=-0.29	mA
Output Power	P <sub>OUT</sub>		<=P5dB	dBm
Channel Temperature	T <sub>ch</sub>		<=200	deg.C

#### ELECTRICAL CHARACTERISTICS \*1 (Case Temperature T<sub>c</sub>=25deg.C)

Item	Symbol	Condition		Unit			
Itelli	Symbol		Min.	Тур.	Max.	onic	
Pinch-off Voltage	V <sub>P</sub>	$V_{DS}$ =50V, $I_{DS}$ =2.64mA	-3.45	-	-2.45	V	
Output Power	P <sub>out</sub> *2	$V_{DS}$ =50V , $I_{DS(DC)}$ =0mA	41.7	42.4	-	dBm	
Drain Efficiency	DE *2	f=3.8GHz, Pin=30.5dBm	50.0	56.0	-	%	
Thermal Resistance	R <sub>th</sub> *3		-	7.2	8.3	deg.C/W	

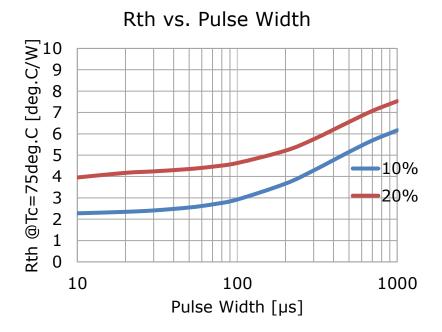
CASE STYLE	Z2K
RoHS Compliance	YES

Note : \*1 : Device screening test items and conditions

- \*2 : 10%-duty RF pulse ( DC supply constant )
- \*3 : Sampling Test : samples size 10pcs. Criteria(accept / reject)=(0 / 1)



# • Thermal Characteristics In Pulsed Operation

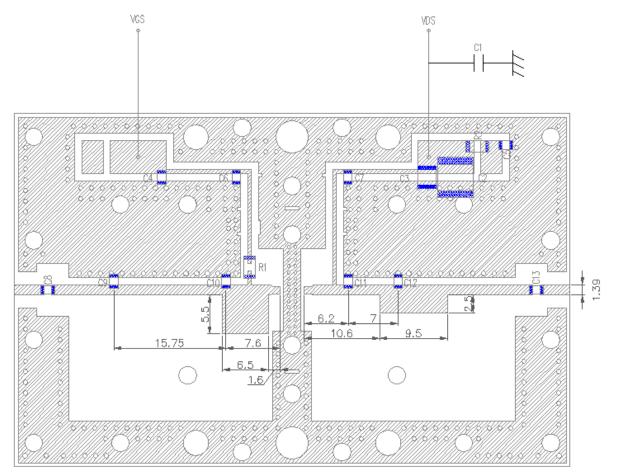


Note : This data included the PCB board (base material CS3376C  $\,$  t=0.6mm Cu=18 $\mu$ m) Channel to Case at 16W PDC



• Electrical characteristics (2.7 to 3.1 GHz)

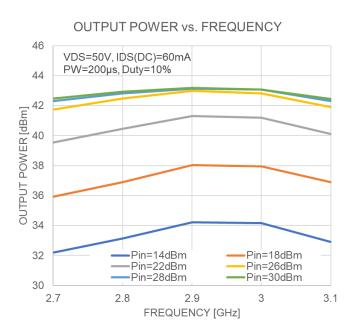
# matching circuit for 2.7 to 3.1 GHz



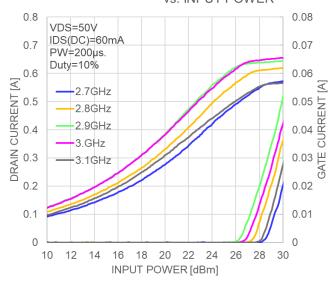
C1	39uF
C2	4.7uF
C3	0.22uF
C4,C5	1000pF
C6,C7,C8,C13	10pF
C9	1.OpF
C10	0.3pF
C11	2.0pF
C12	0.8pF
R1	15ohm
R2	51ohm
PCB	t=0.6mm, ¢r=3.5

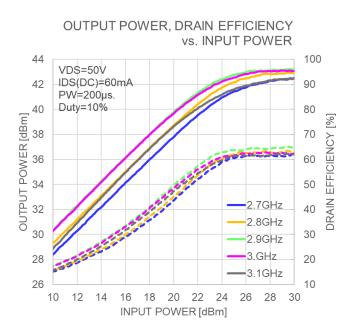


# Electrical characteristics (2.7 to 3.1 GHz)

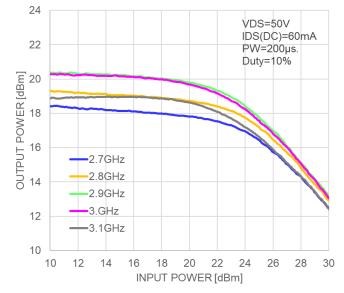


DRAIN CURRENT, GATE CURRENT vs. INPUT POWER





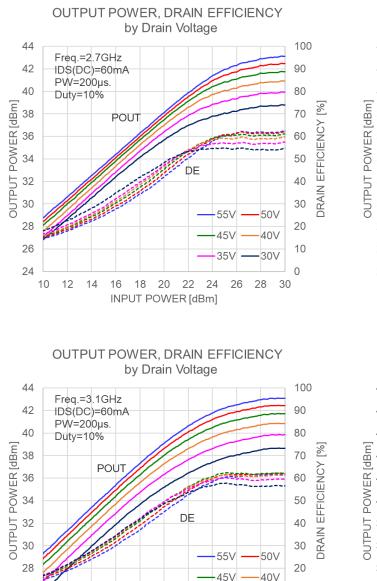
GAIN vs. INPUT POWER

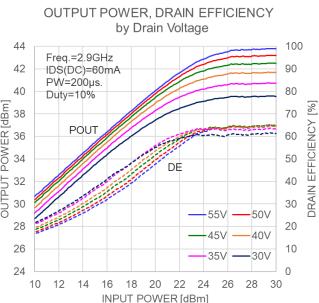




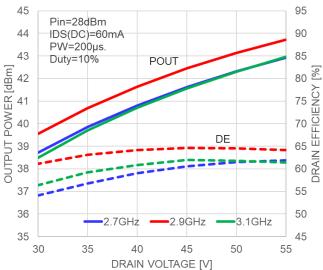
# SGNL015Z2K-R DC – 3.8GHz High Power GaN-HEMT

## Electrical characteristics (2.7 to 3.1 GHz)









26

24

10 12 14 16

10

0

30V

35V

26 28 30

18 20

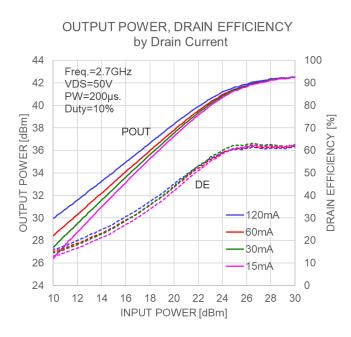
INPUT POWER [dBm]

22 24

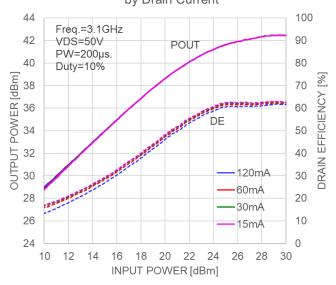


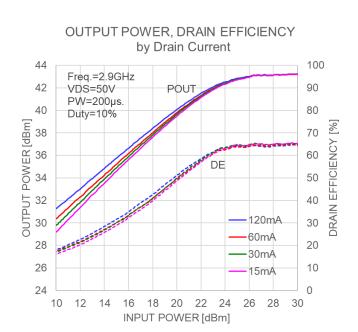
# SGNL015Z2K-R DC – 3.8GHz High Power GaN-HEMT

## Electrical characteristics (2.7 to 3.1 GHz)

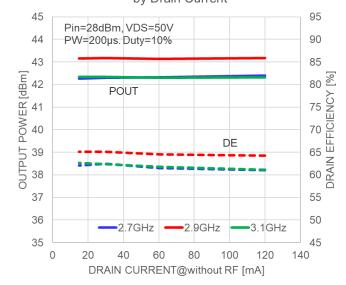


OUTPUT POWER, DRAIN EFFICIENCY by Drain Current





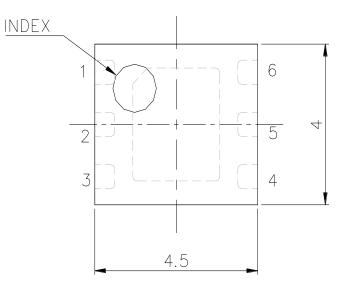
OUTPUT POWER, DRAIN EFFICIENCY by Drain Current

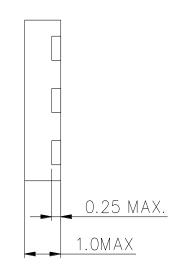


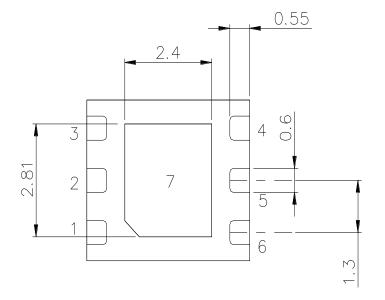


• Package Outline

# Case Style : Z2K







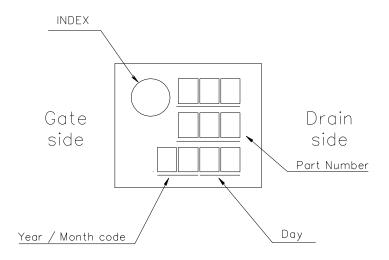
- <Single Type>
  - 1 : NC
  - 2 : Gate
  - 3 : NC
  - 4 : NC
  - 5 : Drain
  - 6 : NC
  - 7 : Source

# Unit:mm Tolerance : ±0.15mm

Edition 2.1 Sep. 2023



## • Package Markings



#### • Year code

Year	2020	2021	2022	2023	2024	2025	2026	2027	2028
Code	С	D	Е	F	G	Н	Ι	J	к

Note: Code letter is cycling 25 alphabet without Q.

#### • Month code

Month	Jan.	Feb.	Mar.	Apr.	Мау	Jun.	Jul.	Aug.	Sep.	Oct.	Nov.	Dec.
Code	Н	М	N	Ρ	R	S	Т	U	W	Х	Y	Z



### ESD characteristic

Test Methodology	Class
Human Body Model (per ANSI/ESDA/JEDEC JS-001-2014)	1B
Charged-Device Model (per ANSI/ESDA/JEDEC JS-002-2014)	C3

#### **Ordering Information**

Part Number	MOQ	MOU	Packing Style
SGNL015Z2K-RT	2500pcs.	2500pcs.	Tape and Reel (12mm width Tape)
SGNL015Z2K-RT1	500pcs.	500pcs.	Tape and Reel (12mm width Tape)
SGNL015Z2K-R	20pcs.	20pcs.	Tray (4-inch)

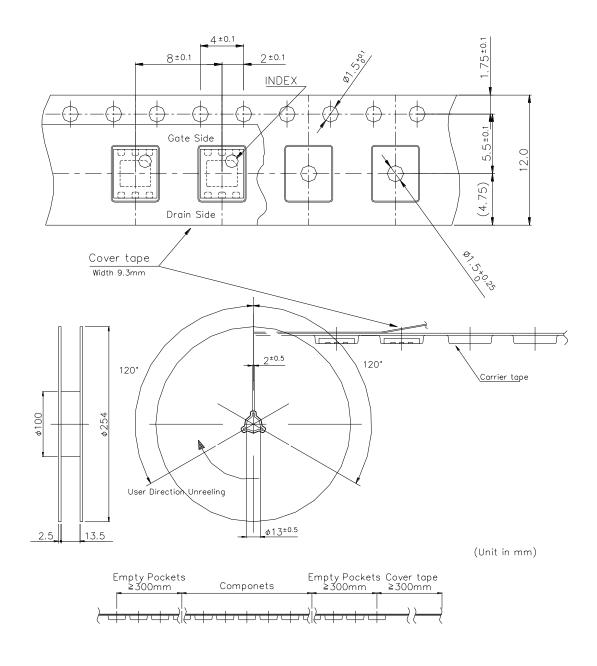
Note : \*MOQ stands for Minimum Order Quantity. \*MOU stands for Minimum Order Unit size.

## **Moisture Sensitivity Level**

Loval	e	
Level	Time	Condition
2	1year after open the package	≤30deg.C/60%RH



## Index and Tape / Reel Configuration (Part Number : SGNL015Z2K-RT, SGNL015Z2K-RT1)



Note : Baking of Tape & Reel material can not baked at 125deg.C.



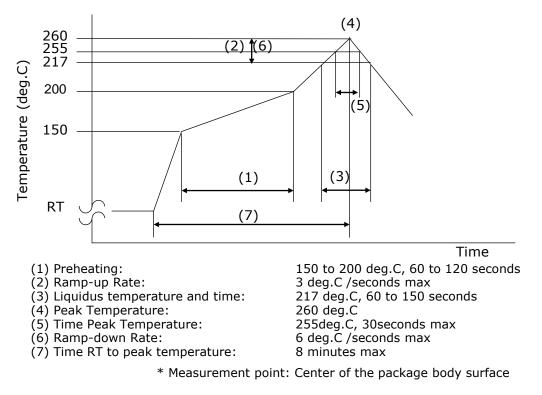
## • Mounting Method of SMD(Surface Mount Devices) for Lead-free solder

#### Mounting Condition

- For soldering, Lead-free solder (Sn-3.0Ag-0.5Cu)\*1 or equivalent shall be used. (\*1: The figure displays with weight %. A predominantly tin-rich alloy with 3.0% silver and 0.5% copper.)
- (2) A rosin type flux with a chlorine content of 0.2% or less shall be used. The rosin flux with low halogen content is recommended.
- (3) When soldering, use one of the following time / temperature methods for acceptable solder joints. Make sure the devices have been properly prepared with flux prior soldering.
  - \* Reflow soldering method (Infrared reflow / Heat circulation reflow / Hot plate reflow):

Limit solder to 3 reflow cycles because resin is used in the modules manufacturing process. Excessive reflow cycles will effect the resin resulting in a potential failure or latent defect. The recommended reflow temperature profile is shown below. The temperature of the reflow profile must be measured at the device body surface.

#### Reflow temperature profile and condition:



(4) The above-recommended conditions were confirmed using the manufacture's equipment and materials. However, when soldering these products, the soldering condition should be verified by customer using their equipment and materials.



## For Safety, Observe the Following Procedures Environmental Management

- Do not put this product into the mouth.
- Do not alter the form of this product into a gas, powder, or liquid through burning, crushing, or chemical processing as these by-products are dangerous to the human body if inhaled, ingested, or swallowed.
- Respect all applicable laws of the country when discarding this product. This product must be disposed in accordance with methods specified by applicable hazardous waste procedures.

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